



# P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a, g</sup>	Q <sub>g</sub> (Typ.)			
	0.020 at V <sub>GS</sub> = - 4.5 V	- 6				
- 20	0.028 at V <sub>GS</sub> = - 2.5 V	.5 V - 6 30 no				
	$0.062 \text{ at V}_{GS} = -1.8 \text{ V}$	- 6				

#### **FEATURES**

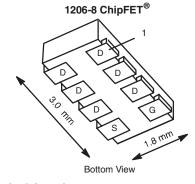
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET<sup>®</sup> Power MOSFET
- Compliant to RoHS Directive 2002/95/EC

# Pb-free

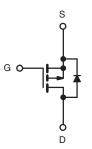
ROHS COMPLIANT HALOGEN

#### **APPLICATIONS**

- Load Switches
  - Notebook
  - Netbook



Ordering Information: Si5471DC-T1-GE3 (Lead (Pb)-free and Halogen-free)



P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATIN</b>	IGS T <sub>A</sub> = 25 °C,	unless othe	erwise noted		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	$V_{DS}$	- 20	V		
Gate-Source Voltage	$V_{GS}$	± 12	v		
	T <sub>C</sub> = 25 °C		- 6 <sup>a</sup>		
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	l <sub>D</sub>	- 6 <sup>a</sup>		
Continuous Diain Current (1) = 130 °C)	T <sub>A</sub> = 25 °C	'D	- 6 <sup>a, b, c</sup>		
	T <sub>A</sub> = 70 °C		- 6 <sup>a, b, c</sup>	A	
Pulsed Drain Current		I <sub>DM</sub>	- 25		
Continuous Source-Drain Diode Current		l <sub>a</sub>	- 5.2		
Continuous Source-Diam Diode Guirent	T <sub>A</sub> = 25 °C	- I <sub>S</sub>	- 2.1 <sup>b, c</sup>		
	T <sub>C</sub> = 25 °C		6.3		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	4	w	
Maximum Fower Dissipation	T <sub>A</sub> = 25 °C	ט י	2.5 <sup>b, c</sup>	v	
	T <sub>A</sub> = 70 °C		1.6 <sup>b, c</sup>		
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	-°C		
Soldering Recommendations (Peak Tempera	-	260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c, d</sup>	t ≤ 5 s	R <sub>thJA</sub>	40	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	15	20	0/11	

#### Notes:

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 95  $^{\circ}\text{C/W}.$
- e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- g.  $T_C = 25$  °C.

# **Si5471DC**

# Vishay Siliconix



SPECIFICATIONS T <sub>J</sub> = 25 °C, unless otherwise noted								
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit		
Static	•							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 20			V		
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 14				
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	Ι <sub>D</sub> = - 250 μΑ		3.4		mV/°C		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	- 0.6		- 1.1	V		
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA		
7 0	,	V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = 0 V			1			
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	25			Α		
		V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 9.1 A		0.0167	0.020			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 2.5 V, I <sub>D</sub> = - 7.7 A		0.023	0.028	Ω		
		V <sub>GS</sub> = - 1.8 V, I <sub>D</sub> = - 1.6 A		0.0365	0.062	=		
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 9.1 A		30		S		
Dynamic <sup>b</sup>				<u> </u>	l			
Input Capacitance	C <sub>iss</sub>			2945				
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		385		pF		
Reverse Transfer Capacitance	C <sub>rss</sub>			370		•		
· · · · · · · · · · · · · · · · · · ·	Qg	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 9.1 A		64	96	nC		
Total Gate Charge		20		30	45			
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 9.1 A		6				
Gate-Drain Charge	Q <sub>gd</sub>			7				
Gate Resistance	R <sub>g</sub>	f = 1 MHz	1	5	10	Ω		
Turn-on Delay Time	t <sub>d(on)</sub>			32	48			
Rise Time	t <sub>r</sub>	$V_{DD} = -10 \text{ V}, R_1 = 1.4 \Omega$		35	53	╡		
Turn-Off Delay Time	t <sub>d(off)</sub>			70	105	-		
Fall Time	t <sub>f</sub>			33	50	1 !		
Turn-on Delay Time	t <sub>d(on)</sub>			9	18	ns		
Rise Time	t <sub>r</sub>	$V_{DD} = -10 \text{ V}, R_{L} = 1.4 \Omega$		8	16	-		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -7.3 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		78	117			
Fall Time	t <sub>f</sub>			22	33			
Drain-Source Body Diode Characteristi	cs			L				
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			5.2			
Pulse Diode Forward Current	I <sub>SM</sub>				25	Α		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 7.3 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.2	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>			25	38	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 70A 41/41 400A/ T 6700		14	21	nC		
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -7.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		11				
Reverse Recovery Rise Time				14		ns		

#### Notes:

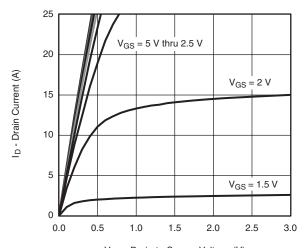
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %

b. Guaranteed by design, not subject to production testing.

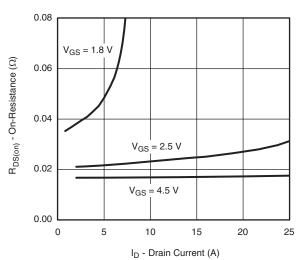


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

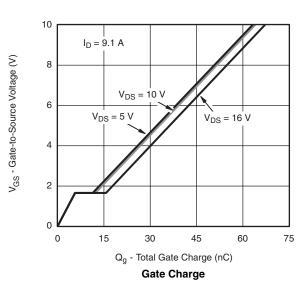


 $V_{DS}$  - Drain-to-Source Voltage (V)

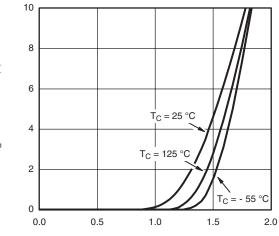
#### **Output Characteristics**



On-Resistance vs. Drain Current

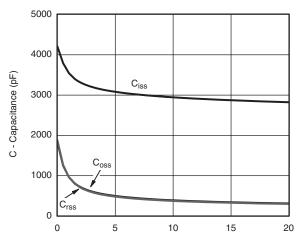


I<sub>D</sub> - Drain Current (A)



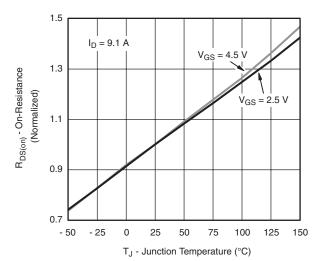
V<sub>GS</sub> - Gate-to-Source Voltage (V)

#### **Transfer Characteristics**



 $V_{DS}$  - Drain-to-Source Voltage (V)

#### Capacitance



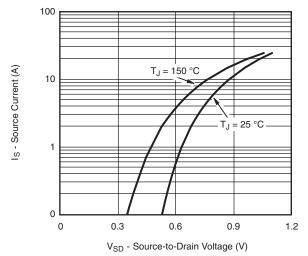
On-Resistance vs. Junction Temperature

# **Si5471DC**

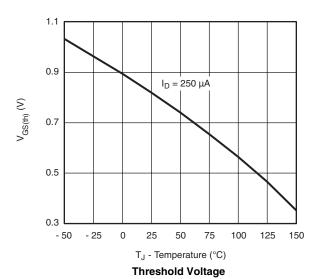
# Vishay Siliconix

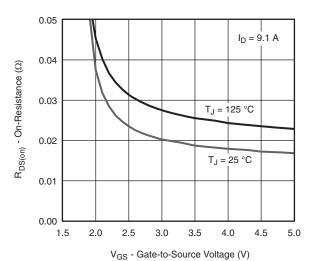
# VISHAY.

#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

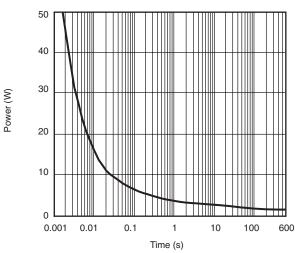


#### Source-Drain Diode Forward Voltage

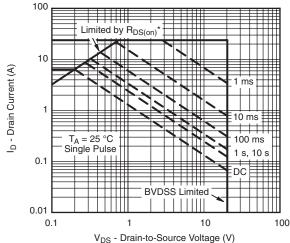




On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power

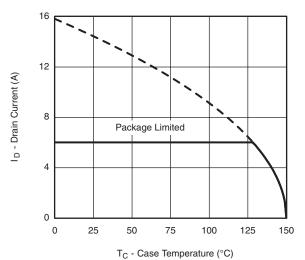


\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

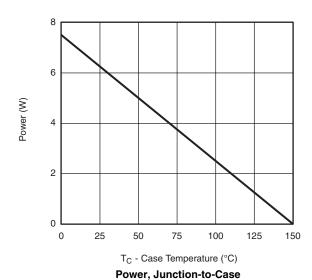
Safe Operating Area, Junction-to-Ambient

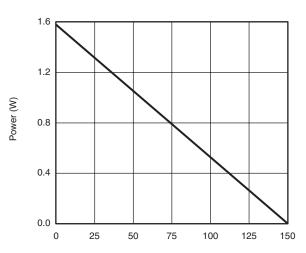


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



#### **Current Derating\***





 $T_A$  - Ambient Temperature (°C)

Power, Junction-to-Ambient

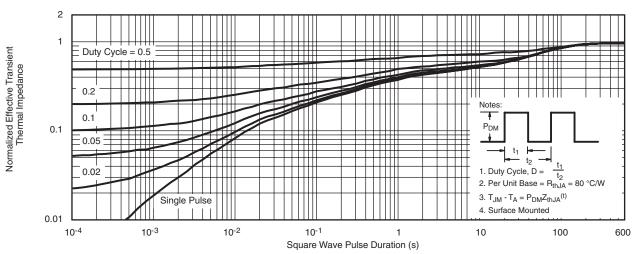
 $<sup>^*</sup>$  The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

## **Si5471DC**

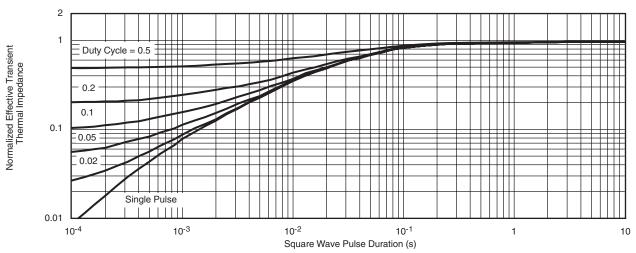
# Vishay Siliconix



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient

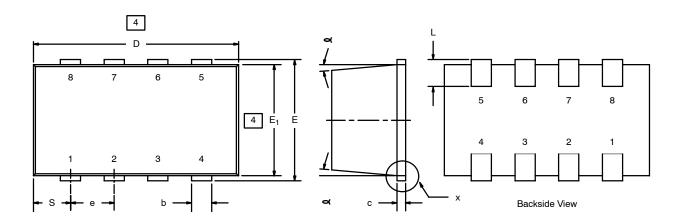


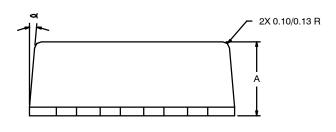
Normalized Thermal Transient Impedance, Junction-to-Foot

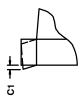
Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, se <a href="www.vishay.com/ppg?64988">www.vishay.com/ppg?64988</a>.



#### 1206-8 ChipFET®







**DETAIL X** 

#### NOTES:

- 1. All dimensions are in millimeaters.
- 2. Mold gate burrs shall not exceed 0.13 mm per side.
- Leadframe to molded body offset is horizontal and vertical shall not exceed
- 4. Dimensions exclusive of mold gate burrs.
- 5. No mold flash allowed on the top and bottom lead surface.

	MIL	LIMET	ERS	INCHES		
Dim	Min	Nom	Max	Min	Nom	Max
Α	1.00	-	1.10	0.039		0.043
b	0.25	0.30	0.35	0.010	0.012	0.014
С	0.1	0.15	0.20	0.004	0.006	0.008
c1	0	-	0.038	0	-	0.0015
D	2.95	3.05	3.10	0.116	0.120	0.122
E	1.825	1.90	1.975	0.072	0.075	0.078
E <sub>1</sub>	1.55	1.65	1.70	0.061	0.065	0.067
е		0.65 BSC		0.0256 BSC		0
L	0.28	-	0.42	0.011	-	0.017
S	0.55 BSC			0.022 BSC		
9	5°Nom			5°Nom		
ECN: C-03528—Rev. F, 19-Jan-04 DWG: 5547						

www.vishay.com 15-Jan-04





# Single-Channel 1206-8 ChipFET® Power MOSFET Recommended Pad Pattern and Thermal Performance

#### INTRODUCTION

New Vishay Siliconix ChipFETs in the leadless 1206-8 package feature the same outline as popular 1206-8 resistors and capacitors but provide all the performance of true power semiconductor devices. The 1206-8 ChipFET has the same footprint as the body of the LITTLE FOOT® TSOP-6, and can be thought of as a leadless TSOP-6 for purposes of visualizing board area, but its thermal performance bears comparison with the much larger SO-8.

This technical note discusses the single-channel ChipFET 1206-8 pin-out, package outline, pad patterns, evaluation board layout, and thermal performance.

#### **PIN-OUT**

Figure 1 shows the pin-out description and Pin 1 identification for the single-channel 1206-8 ChipFET device. The pin-out is similar to the TSOP-6 configuration, with two additional drain pins to enhance power dissipation and thermal performance. The legs of the device are very short, again helping to reduce the thermal path to the external heatsink/pcb and allowing a larger die to be fitted in the device if necessary.

#### Single 1206-8 ChipFET

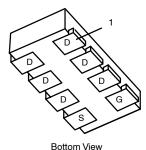


FIGURE 4

FIGURE 1.

For package dimensions see the 1206-8 ChipFET package outline drawing (http://www.vishay.com/doc?71151).

#### **BASIC PAD PATTERNS**

The basic pad layout with dimensions is shown in Application Note 826, *Recommended Minimum Pad Patterns With Outline Drawing Access for Vishay Siliconix MOSFETs*, (http://www.vishay.com/doc?72286). This is sufficient for low power dissipation MOSFET applications, but power semiconductor performance requires a greater copper pad area, particularly for the drain leads.

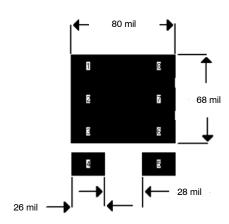


FIGURE 2. Footprint With Copper Spreading

The pad pattern with copper spreading shown in Figure 2 improves the thermal area of the drain connections (pins 1,2,3,6.7,8) while remaining within the confines of the basic footprint. The drain copper area is 0.0054 sq. in. or 3.51 sq. mm). This will assist the power dissipation path away from the device (through the copper leadframe) and into the board and exterior chassis (if applicable) for the single device. The addition of a further copper area and/or the addition of vias to other board layers will enhance the performance still further. An example of this method is implemented on the Vishay Siliconix Evaluation Board described in the next section (Figure 3).

# THE VISHAY SILICONIX EVALUATION BOARD FOR THE SINGLE 1206-8

The ChipFET 1206-08 evaluation board measures 0.6 in by 0.5 in. Its copper pad pattern consists of an increased pad area around the six drain leads on the top-side—approximately 0.0482 sq. in. 31.1 sq. mm—and vias added through to the underside of the board, again with a maximized copper pad area of approximately the board-size dimensions. The outer package outline is for the 8-pin DIP, which will allow test sockets to be used to assist in testing.

The thermal performance of the 1206-8 on this board has been measured with the results following on the next page. The testing included comparison with the minimum recommended footprint on the evaluation board-size pcb and the industry standard one-inch square FR4 pcb with copper on both sides of the board.

Document Number: 71126 www.vishay.com



Front of Board

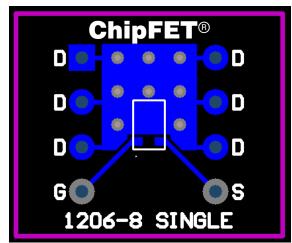




FIGURE 3.

#### THERMAL PERFORMANCE

#### **Junction-to-Foot Thermal Resistance** (the Package Performance)

Thermal performance for the 1206-8 ChipFET measured as junction-to-foot thermal resistance is 15°C/W typical, 20°C/W maximum for the single device. The "foot" is the drain lead of the device as it connects with the body. This is identical to the SO-8 package  $R_{\Theta if}$  performance, a feat made possible by shortening the leads to the point where they become only a small part of the total footprint area.

#### **Junction-to-Ambient Thermal Resistance** (dependent on pcb size)

The typical  $R_{\Theta ja}$  for the single-channel 1206-8 ChipFET is 80°C/W steady state, compared with 68°C/W for the SO-8. Maximum ratings are 95°C/W for the 1206-8 versus 80°C/W for the SO-8.

#### **Testing**

To aid comparison further, Figure 4 illustrates ChipFET 1206-8 thermal performance on two different board sizes and three different pad patterns. The results display the thermal performance out to steady state and produce a graphic account of how an increased copper pad area for the drain connections can enhance thermal performance. The measured steady state values of  $R_{\Theta ja}$  for the single 1206-8 ChipFET are:

1) Minimum recommended pad pattern (see Figure 2) on the evaluation board size of 0.5 in x 0.6 in.	156°C/W	
2) The evaluation board with the pad pattern described on Figure 3.	111°C/W	
3) Industry standard 1" square pcb with maximum copper both sides.	78°C/W	

The results show that a major reduction can be made in the thermal resistance by increasing the copper drain area. In this example, a 45° C/W reduction was achieved without having to increase the size of the board. If increasing board size is an option, a further 33°C/W reduction was obtained by maximizing the copper from the drain on the larger 1" square pcb.

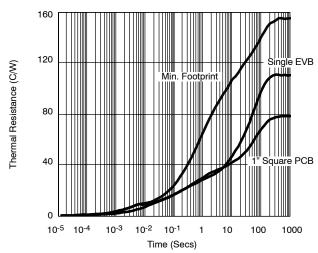


FIGURE 4. Single 1206-8 ChipFET

#### **SUMMARY**

The thermal results for the single-channel 1206-8 ChipFET package display similar power dissipation performance to the SO-8 with a footprint reduction of 80%. Careful design of the package has allowed for this performance to be achieved. The short leads allow the die size to be maximized and thermal resistance to be reduced within the confines of the TSOP-6 body size.

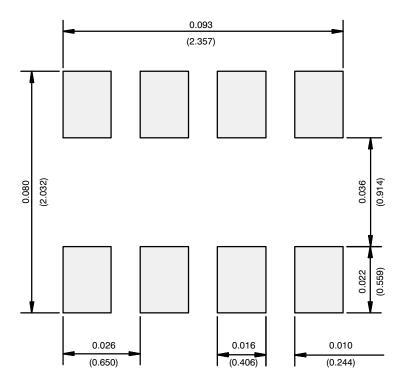
#### ASSOCIATED DOCUMENT

1206-8 ChipFET Dual Thermal performance, (http://www.vishay.com/doc?71127).

Document Number: 71126 www.vishav.com



## RECOMMENDED MINIMUM PADS FOR 1206-8 ChipFET®



Recommended Minimum Pads Dimensions in Inches/(mm)

Return to Index

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## **Material Category Policy**

Vishay Intertechnology, Inc. hereby certifies that all its products that are identified as RoHS-Compliant fulfill the definitions and restrictions defined under Directive 2011/65/EU of The European Parliament and of the Council of June 8, 2011 on the restriction of the use of certain hazardous substances in electrical and electronic equipment (EEE) - recast, unless otherwise specified as non-compliant.

Please note that some Vishay documentation may still make reference to RoHS Directive 2002/95/EC. We confirm that all the products identified as being compliant to Directive 2002/95/EC conform to Directive 2011/65/EU.